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## ***Damage to VUV, EUV, and X-ray Optics VI***

**Libor Juha  
Saša Bajt  
Regina Soufli**  
*Editors*

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# Contents

v	Authors
vii	Conference Committee

---

## DAMAGE TO OPTICS I

10236 05	<b>A finite element approach to x-ray optics design</b> [10236-4]
----------	---

---

## DAMAGE TO OPTICS II

10236 0D	<b>Growth of nano-dots on the grazing incidence mirror surface under FEL irradiation: analytic approach to modeling (Invited Paper)</b> [10236-13]
10236 0E	<b>Low-pressure RF remote plasma cleaning of carbon-contaminated B<sub>4</sub>C-coated optics</b> [10236-14]
10236 0F	<b>Study of performance loss of Lyman alpha filters due to chemical contamination</b> [10236-15]

---

## THEORY OF DAMAGE

10236 0H	<b>Classical Monte-Carlo simulations of x-ray induced electron cascades in various materials (Invited Paper)</b> [10236-18]
10236 0I	<b>Influence of model parameters on a simulation of x-ray irradiated materials: example of XTANT code</b> [10236-19]

---

## POSTER SESSION

10236 0J	<b>Formation of periodic relief at Sc/Si multilayer surface under EUV laser irradiation</b> [10236-8]
10236 0K	<b>Optical and structural characterization of Nb, Zr, Nb/Zr, Zr/Nb thin films on Si<sub>3</sub>N<sub>4</sub> membranes windows</b> [10236-16]



# Authors

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Ahmed, Nadeem, 0K  
Artyukov, I. A., 0J  
Auchère, Frédéric, 0F  
Barrett, R., 0E  
Buzmakov, A. V., 0D  
Carlino, V., 0E  
Devizenko, A. Y., 0J  
Dietsch, R., 0E  
Etcheto, Pierre, 0F  
Faye, Delphine, 0F  
Ferrero, C., 05  
Gaballah, A. E. H., 0K  
Guigay, J. P., 05  
Honkanen, A. P., 05  
Jimenez, K., 0K  
Kondratenko, V. V., 0J  
Kozhevnikov, I. V., 0D  
Lipp, Vladimir, 0H, 0I  
Medvedev, Nikita, 0H, 0I  
Mocella, V., 05  
Moreno Fernández, H., 0E  
Nicolosi, P., 0K  
Pellegrin, E., 0E  
Pershyn, Y. P., 0J  
Rocca, J. J., 0J  
Rogler, D., 0E  
Samoylova, L., 0D  
Sauthier, G., 0E  
Siewert, F., 0D  
Sinn, H., 0D  
Störmer, M., 0D  
Thomasset, M., 0E  
Tiedtke, K., 0D  
Vinogradov, A. V., 0J  
Zhang, Xueyan, 0F  
Ziaja, Beata, 0H  
Zolotaryov, A., 0J  
Zuppella, P., 0K



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- 1 Damage to Optics I  
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- 3 Damage to Samples  
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